FEATURES

- DOUBLE LAYER CONSTRUCTION
- POWER BACK-UP FOR CMOS DEVICES
- SURFACE MOUNTABLE V-CHIP STYLE
- LEAD-FREE FINISH

RoHS Compliant High Temperature Reflow +260°C



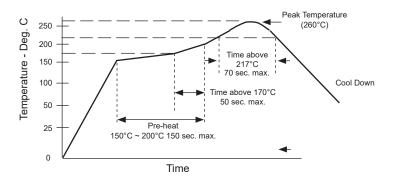
CHARACTERISTICS

Rated Voltage Range	3.5 & 5.5VDC				
Rated Capacitance Range	0.047F ~ 0.47F (47,000μF ~ 470,000μF)	Super Capacitor			
Operating Temp. Range	-40°C ~ +85°C	Application Guide			
Capacitance Tolerance	+80%/-20% (Z)				
1 11:5 -	Δ Capacitance Change	Within ±30% of initia	al measured value		
Load Life Test +85°C 240 hours	Maximum ESR	Less than 200% of the specified maximum value			
200 0 240 110413	Current at 30 minutes	Less than 200% of the sp	Less than 200% of the specified maximum value		
T	Δ Capacitance Change	Within +80%/-20% of specified value			
Temperature Cycling (5 cycles, -25 ~ +70°C	Maximum ESR	Less than specified maximum value			
(0 0)0100, 20 170 0	Current at 30 minutes	Less than specified	l maximum value		
	Δ Capacitance Change	Within ±20% of initial measured value			
Humidity Resistance	Maximum ESR	Less than 120% of the specified maximum value			
(240 hours @ 40°C/90% RH)	Current at 30 minutes	Less than 120% of the sp	ecified maximum value		

STANDARD VALUES AND SPECIFICATIONS

NIC P/N	Capacitance Value (F) Discharge	Working Voltage (VDC)	Max. Current @ 30 minutes (mA)	Max. ESR @ 1KHz (Ω)
NEXCW104Z3.5V10.7X5.5TRF	0.10	3.5	0.090	100
NEXCW224Z3.5V10.7X5.5TRF	0.22	3.5	0.200	50
NEXCW474Z3.5V10.7X8.5TRF	0.47	3.5	0.420	50
NEXCW473Z5.5V10.7X5.5TRF	0.047	5.5	0.071	100
NEXCW104Z5.5V10.7X5.5TRF	0.10	5.5	0.150	50
NEXCW224Z5.5V10.7X8.5TRF	0.22	5.5	0.330	50

HIGH TEMPERATURE REFLOW PROFILE



Peak Temperature	+260°C
Time above +255°C	10 sec. max.
Time above +230°C	45 sec. max.
Time above +220°C	60 sec. max.
Time above +217°C	70 sec. max.
150°C ~ +200°C (with time above +170°C 50 sec. max.)	150 sec. max.

- 1. The temperatures shown are the surface temperature values on the top of the can and on the capacitor terminals.
- 2. 2x reflow process maximum. Capacitor should be allowed to return to room temperature before second reflow process.

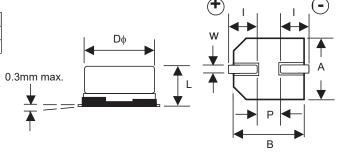
PRECAUTIONS

Please review the notes on correct use, safety and precautions found at https://www.niccomp.com/resource/files/double/Double_Layer_Capacitor_Guide_0810-RevBrA7.pdf If in doubt or uncertainty, please review your specific application - process details with NIC's technical support personnel: tpmg@niccomp.com



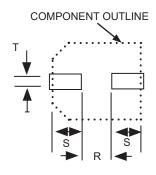
CASE DIMENSIONS (mm)

Case Size	Dφ ±	L max.	A/B ±0.2	I	W	Р
10.7 x 5.5	10.7	5.5	10.8	3.9 ±0.5	1.2 ± 0.1	5.0
10.7 x 8.5	10.7	8.5	10.8	3.9 ±0.5	1.2 ± 0.1	5.0



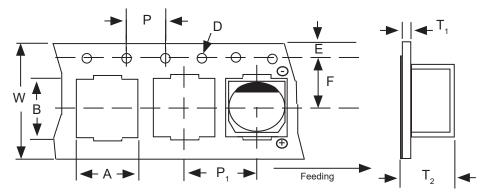
LAND PATTERN DIMENSIONS (mm)

Case Diameter	R	S	Т
10.7	5.0	4.9	2.5



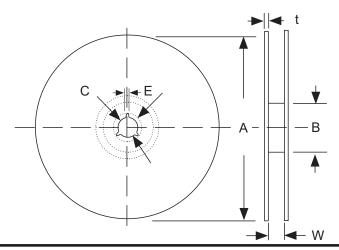
CARRIER TAPE DIMENSIONS (mm)

Case Size	Α	В	D	E	F	Р	P₁	T,	T ₂	W	Quantity/Reel
10.7 x 5.5	11.4	13.0	1.55	1.75	11.5	4.0	16.0	0.4	6.0	24.0	1,000
10.7 x 8.5	11.4	13.0	1.55	1.75	11.5	4.0	16.0	0.4	8.4	24.0	500



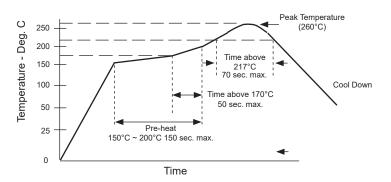
REEL DIMENSIONS (mm)

Case Size	A ± 2.0	B ± 1.0	C ± 0.5	D ± 0.8	E ± 0.5	W	t
10.7 x 5.5	380	80.0	13.0	21.0	2.0	25.5 ± 0.5	2.0
10.7 x 8.5	380	100.0	13.0	21.0	2.0	25.5 ± 1.0	2.0





HIGH TEMPERATURE REFLOW PROFILE

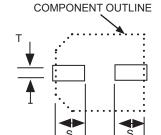


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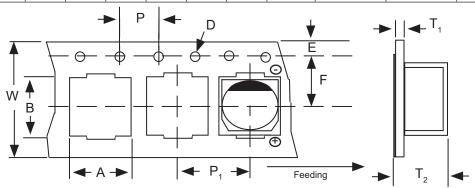
LAND PATTERN DIMENSIONS (mm)

Case Diameter	R	S	Т
10.7	5.0	4.9	2.5



CARRIER TAPE DIMENSIONS (mm)

Case Size	Α	В	D	Е	F	G	Р	P,	T,	T,	W	Quantity/Reel
10.7 x 5.5	11.4	13.0	1.55	1.75	11.5	-	4.0	16.0	0.4	6.0	24.0	1,000



REEL DIMENSIO	NS (mm)							
Case Size	A ± 2.0	B ± 1.0	C ± 0.5	D ± 0.8	E ± 0.5	W	t	
10.7 x 5.5	380	80.0	13.0	21.0	2.0	25.5	3.0	
Π c				C	◆E	A A		<u>↓</u> - B <u>↓</u>

V-Chip Memory Back-Up Capacitors

RELIABILITY TEST

Item		Specif	ication	Test Method JIS C 5260-1
	040	Capacitance	>50% of initial measured value	
	Step 2	ESR	<400% of initial measured value	Section 4.17
	Chair 0	Capacitance	>30% of initial measured value	Phase 1: +25°C ± 2°C
	Step 3	ESR	<700% of initial measured value	Phase 2: -25°C ± 2°C
Temperature Characteristics		Capacitance	>200% of initial measured value	Phase 3: -40°C ± 2°C
remperature Characteristics	Step 5	ESR	Meets initial specification	
		Current @ 30 minutes	1.5CV (mA) or less	Phase 4: +25°C ± 2°C
		Capacitance	±20% of initial measured value*	Phase 5: +85°C ± 2°C
	Step 6	ESR	Meets initial specification*	Phase 6: +25°C ± 2°C
		Current after 30 minutes	Meets initial specification*	
		Capacitance		Section 4.13
Vibration		ESR	Meets initial specifications	Frequency: 10 ~ 55Hz
Vibration	Cu	rrent after 30 minutes		
		Appearance	No obvious abnormalities	Duration: 6 hours
		Capacitance		
Resistance to Soldering Heat		ESR	Meets initial specifications*	See NEXCW datasheet for reflow
resistance to coldening fleat	Cu	rrent after 30 minutes		soldering conditions
		Appearance	No obvious abnormalities	
		Capacitance		Section 4.12
Temperature Cycling		ESR	Meets initial specifications*	Temp.: -40°C > +25°C > +85°C
remperature Cycling	Cu	rrent after 30 minutes		Number of cycles: 5
		Appearance	No obvious abnormalities	l l l l l l l l l l l l l l l l l l l
		Capacitance	±20% of initial measured value*	Section 4.14
Resistance to		ESR	<120% of initial specified value*	Temperature: +40°C ± 2°C
High Temperature & Humidity	Cu	rrent after 30 minutes	<120% of initial specified value*	Relative Humidity: 90% ~ 95%
		Appearance	No obvious abnormalities	Duration: 240 hours ± 8 hours
		Capacitance	±30% of initial measured value*	Section 4.15
		ESR	<200% of initial specified value*	Temperature: +85°C ± 2°C
High Temperature Load Life	Cu	rrent after 30 minutes	<200% of initial specified value*	Voltage: 5.5Vdc
High Temperature Load Life				Series resistance: 0Ω
		Appearance	No obvious abnormalities	Duration: 240 hours +8/-0 hours

^{*} Stablize component at +25°C prior to making measurements of characteristics.